



SEMI® International Standards Program

Compound Semiconductor Technical Committee Meeting

Virtual Meeting (Videoconference)

**Wednesday 03rd May 2023,
16:30 CEST / 7:30 am PDT / 23:30 J**

V1 30.03.2023

Co-chairs:

- [Dr. Arnd-Dietrich Weber, SiCrystal](#)
- [N.N.](#)

European Compound Semiconductor Committee Meeting (Virtual Meeting)

16:30	Welcome and Self-Introductions	all
16:40	SEMI Standards Overview and Legal Reminders	SEMI Staff
16:45	Review of the minutes and action items from the previous meeting	SEMI Staff
16:55	Task Force Reports (~5 minutes each) <ul style="list-style-type: none">• SiC-Task Force• 5-year Review (M46, M63, M75) Task Force• XRT Test Method for SiC -Task Force	A. Weber H.C. Alt C. Kranert
17:10	New Activity: 5y review: SEMI M81-0418: Guide to Defects Found in Monocrystalline Silicon Carbide Substrates	A. Weber
17:20	Ballot Submission: new Document "Test Method for Quantifying Basal Plane Dislocations in 4H-SiC by X-ray Topography" (C. Kranert) /XRT Test Method for SiC -Task Force	C. Kranert
17:40	Ballot submission 5-year Task Force: M63 - Test Method for Measuring the Al Fraction in AlGaAs on GaAs Substrates by High Resolution X-Ray Diffraction	H.C. Alt
18:00	Compound Materials Liaison Reports <ul style="list-style-type: none">• North America• Japan• China	SEMI Staff
18:10	New Business: <ul style="list-style-type: none">• Review of document-status and upcoming-reviews• Review/discussion of recently submitted ballots on SiC test methods• Open discussion	A. Weber A. Weber N.N.
18:20	Any Other Business / Questions	A. Weber
18:25	Next Meetings	
18:30	End	